New results from T2K experiment

Ken Sakashita for T2K collaboration 2011/June/15, KEK Physics Seminar

T2K Collaboration





International collaboration (~500 members, 59 institutes, 12 countries)

T2K (Tokai-to-Kamioka) experiment



T2K Main Goals:

\star Discovery of $v_{\mu} \rightarrow v_{e}$ oscillation (v_{e} appearance)

\star Precision measurement of v_{μ} disappearance

CP odd term in $v_{\mu} \rightarrow v_e$ **prob.** $\propto \sin \delta \cdot s_{12} \cdot s_{23} \cdot s_{13}$

Overview of this talk

- 1. Introduction of T2K experiment
- 2. Search for v_e appearance with 1.43 x 10²⁰ protons on target (p.o.t.)
 - Analysis overview
 - v_e selection criteria
 - The expected number of events at Far detector
 - Systematic uncertainty
 - Observation at Far detector & Results
- 3. Conclusion

(Previous results w/ 0.32 x 10²⁰ p.o.t.)

Physics Motivation of ν_e appearance

\star discovery of $v_{\mu} \rightarrow v_{e}$

Direct detection of neutrino flavor mixing in "appearance" mode

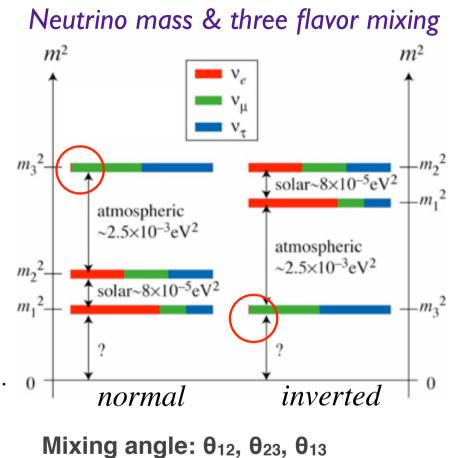
Determine θ₁₃

The last mixing angle θ_{13} can be determined by $v_{\mu} \rightarrow v_{e}$

$$P(v_{\mu} \rightarrow v_{e}) = \sin^{2}2\theta_{13} \sin^{2}\theta_{23} \sin^{2}(\Delta m_{31}^{2} L/4E) + ...$$
$$(\Delta m_{23}^{2} \sim \Delta m_{31}^{2})$$

Open a possibility to measure CP violation in lepton sector

CPV term in P($v_{\mu} \rightarrow v_{e}$) $\propto sin\theta_{12}sin\theta_{13}sin\theta_{23}sin\delta$



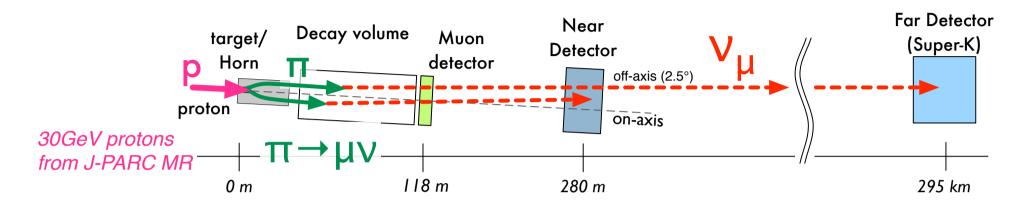
 $\theta_{12} = 34^{\circ} \pm 3^{\circ} \qquad \theta_{23} = 45^{\circ} \pm 5^{\circ}$

Last unknown mixing angle θ₁₃

 $sin^2 2\theta_{13} < 0.15$ at 90% C.L.

CHOOZ (reactor exp.) and MINOS (accelerator exp.)

Design Principle of T2K



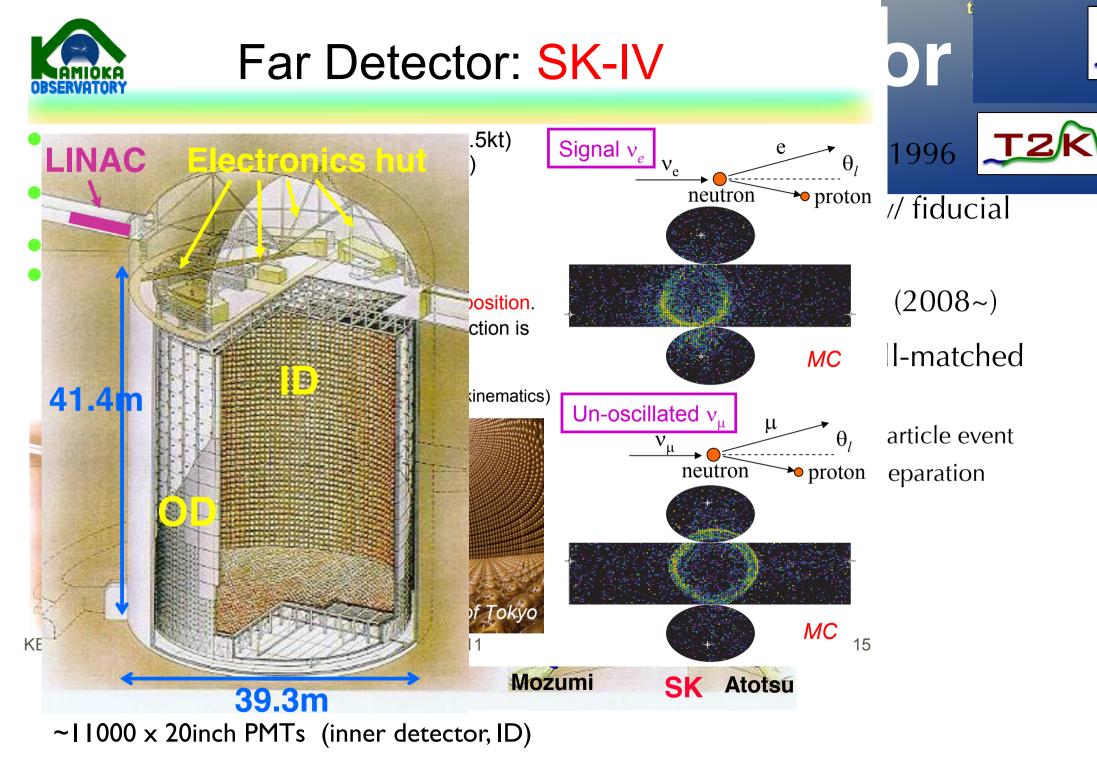
Super-Kamiokande(SK) as far neutrino detector

- Excellent performance for single particle event
 - $v_e + n \rightarrow e + p$ (T2K v_e signal)
 - This event is dominant at sub GeV beam
- Need to reduce high energy tail (reduce background)
- Need high intensity

 \rightarrow Off-axis beam (The first operational long-baseline off-axis \vee beam)

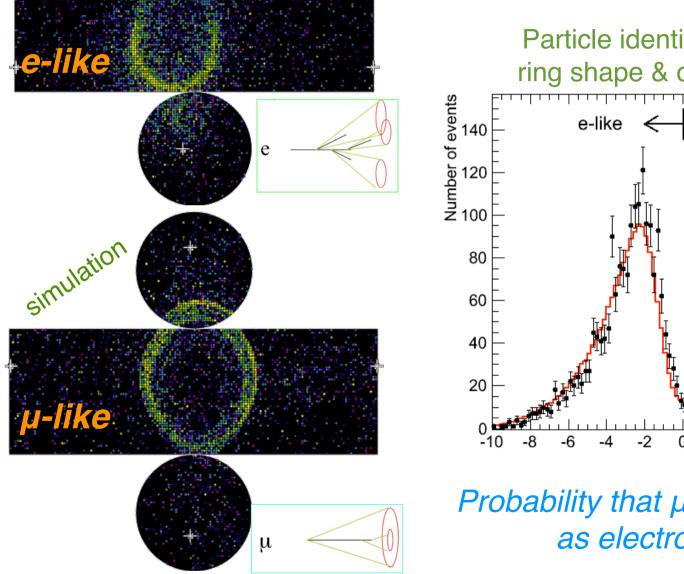
e

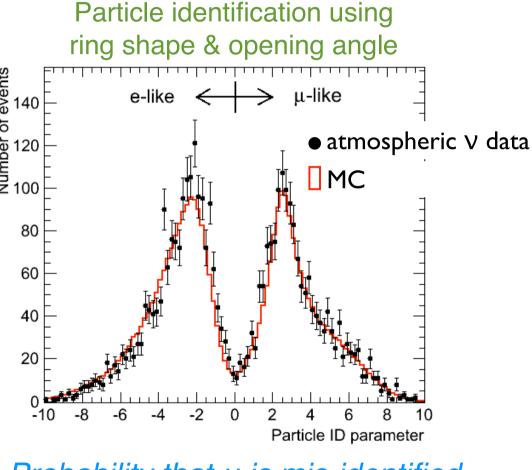
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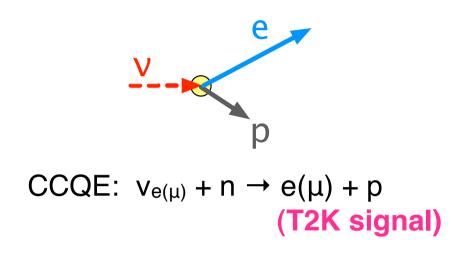
Electron-like and muon-like event at SK





Probability that μ is mis-identified as electron is ~1%

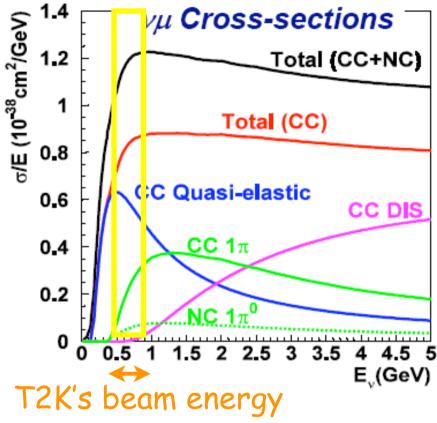
Charged Current Quasi-elastic (CCQE) interactions dominate at sub GeV



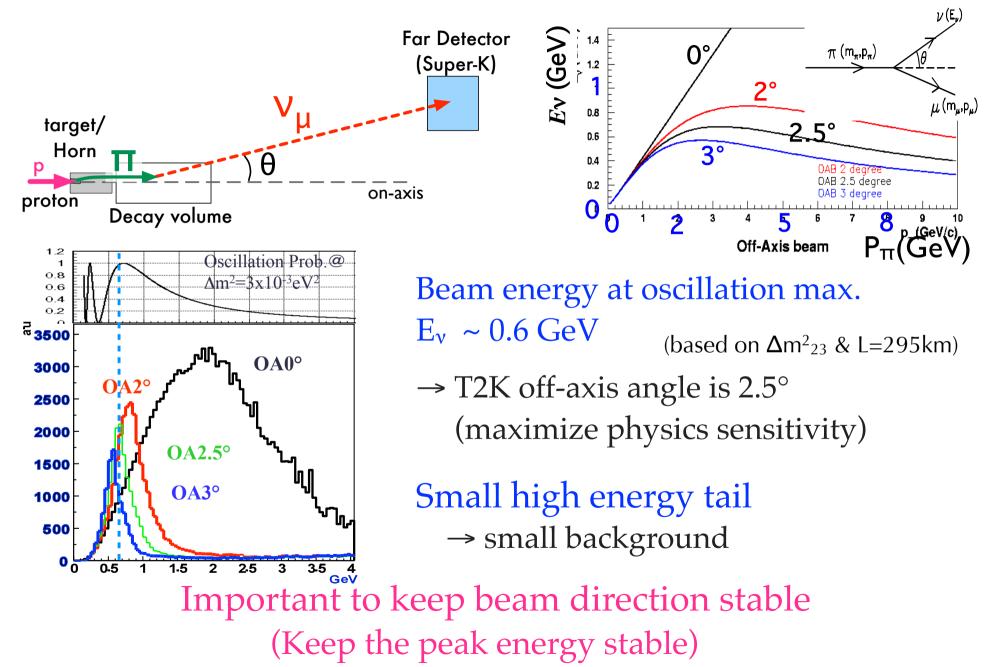
v interactions at high energy cause background events in T2K (e.g. NC1 π^0 is one of v_e background)

 \rightarrow need to reduce high energy \vee

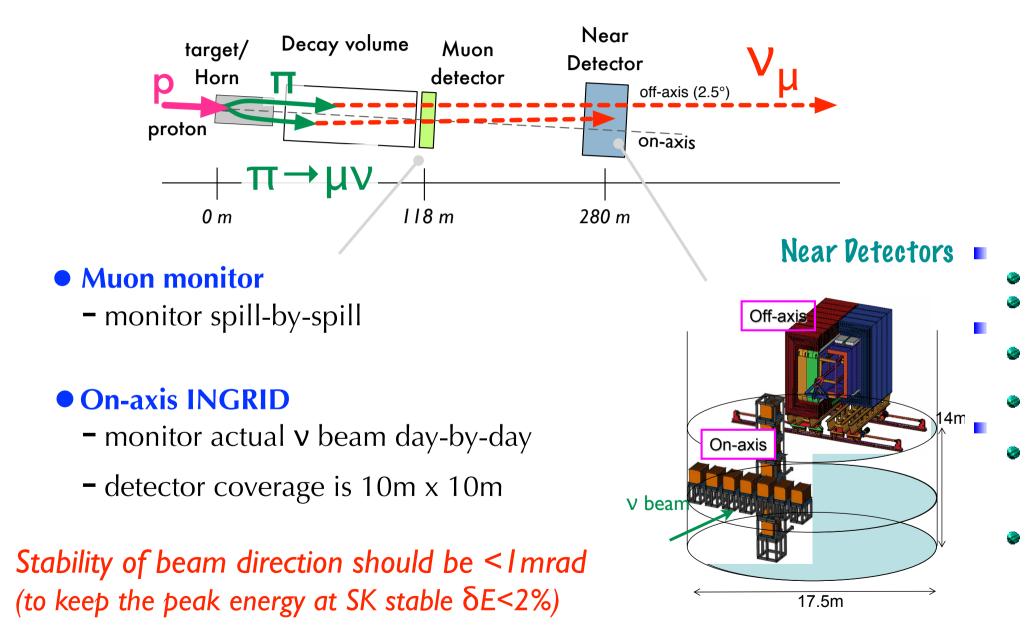




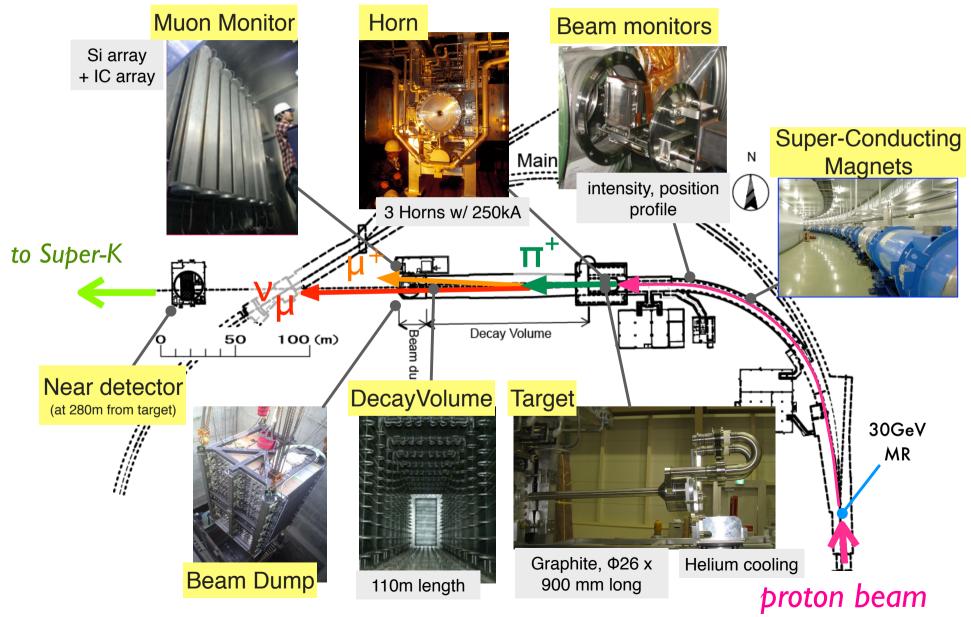
Off-axis beam : intense & narrow-band beam



Monitor beam direction and intensity



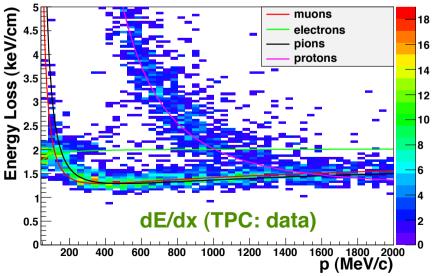
J-PARC Neutrino beam facility

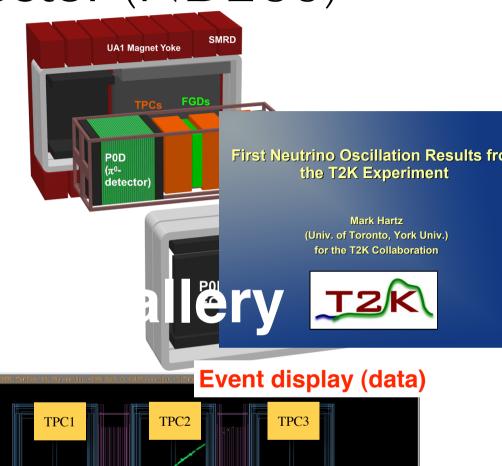


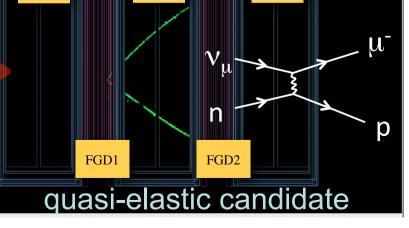
Off-axis Near Detector (ND280)

v_µ CC events rate measurement in present analysis

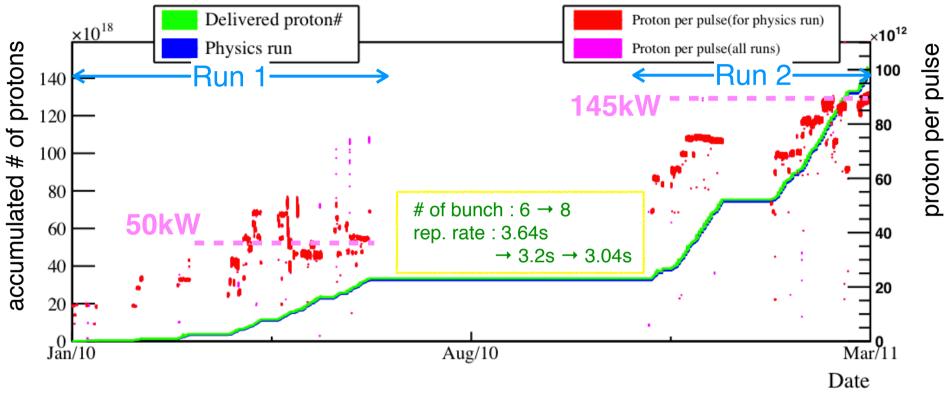
- 0.2 T UA1 magnet
- Fine Grained Detector (FGD)
 - scintillator bars target (water target in FGD2)
 - 1.6ton fiducial mass for analysis
- N I mue Projection Chambers (TPC)
 - better than 10% dE/dx resolution
 - 10% momentum resolution at 1GeV/c







Total # of protons used for analysis



Run 1 (Jan. '10 - June '10)

- 3.23 x 10^{19} p.o.t. for analysis
- 50kW stable beam operation

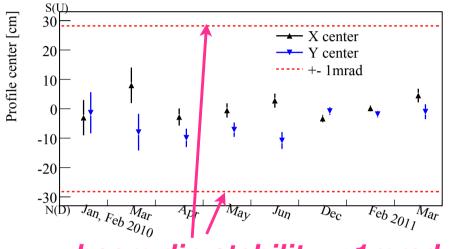
Run 2 (Nov. '10 - Mar. '11)

- 11.08 x 10¹⁹ p.o.t. for analysis
- ~145kW beam operation

Total # of protons used for this analysis is 1.43 x 10²⁰ pot 2% of T2K's final goal and ~5 times exposure of the previous report

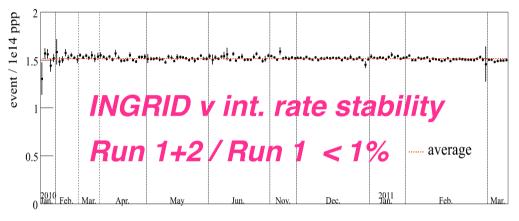
v beam stability

Stability of v beam direction (INGRID)

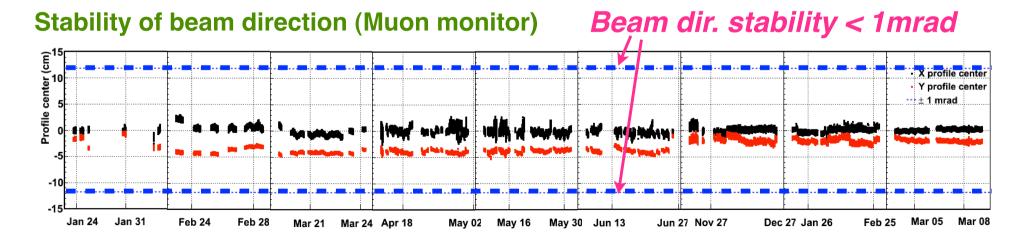


v beam dir. stability < 1mrad

Stability of v interaction rate normalized by # of protons (INGRID)



integrated day(1 data point / 1 day)



Search for v_e appearance

Analysis overview

- 1. Apply $\nu_{\rm e}$ selection criteria to the events at far detector (SK)
- 2. Compare the observed number of events and the expected number of events (for $\sin^2 2\theta_{13}=0$)
 - \rightarrow search for ν_e appearance

Contents in this section

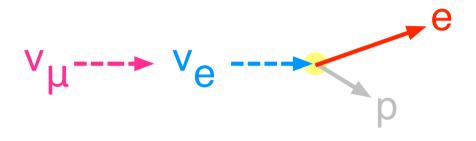
- \Rightarrow v_e selection criteria
- The expected number of events at Far detector using *Hadron (pion) production measurement* & ND event rate measurement
- ∻ Systematic uncertainty
- * Observation at Far detector & Results

v_e selection criteria

- The expected number of events at Far detector
- Systematic uncertainty
- Observation at Far detector & Results

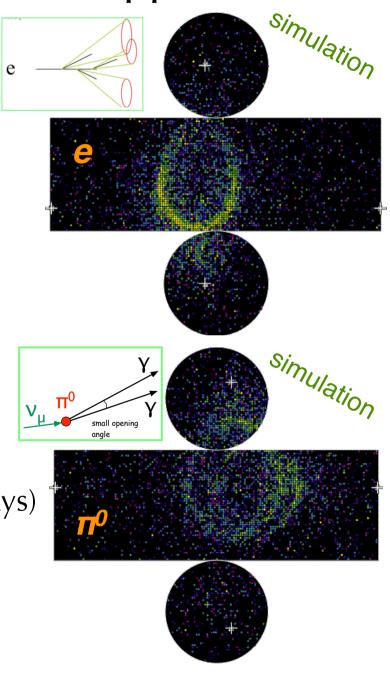
T2K Signal & Background for $\nu_{\rm e}$ appearance

- Signal = single electron event
 - oscillated $\nu_{\rm e}$ interaction :



 $CCQE : v_e + n \rightarrow e + p$ (dominant process at T2K beam energy)

- Background
 - intrinsic $\nu_{\rm e}$ in the beam (from $\mu,$ K decays)
 - π^0 from NC interaction



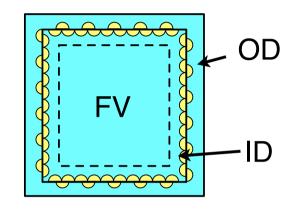
v_e selection at far detector (SK)

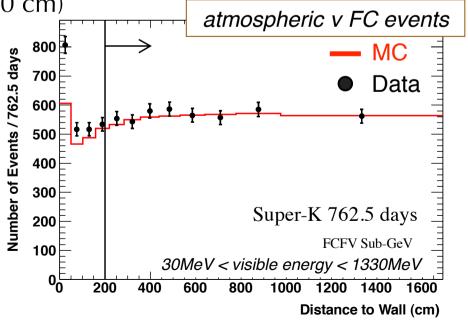
The selection criteria were optimized for initial running condition

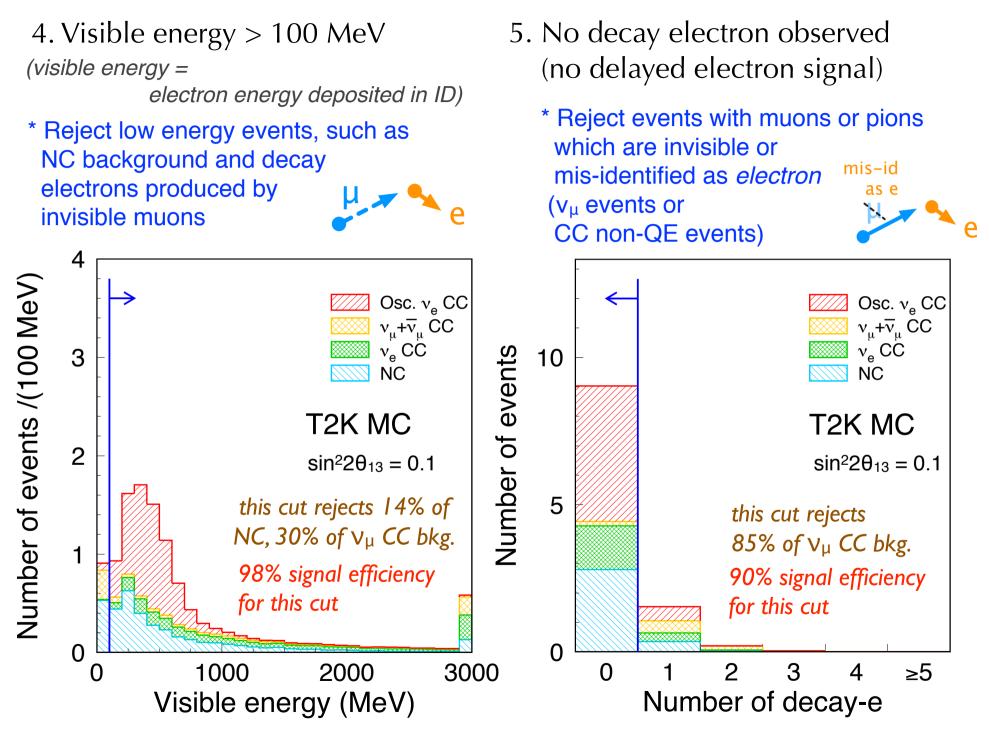
The selection criteria were fixed before data taking started to avoid bias

7 selection cuts

- 1. T2K beam timing & Fully contained (FC) (synchronized with the beam timing, no activities in the OD)
- 2. In fiducial volume (FV) (distance btw recon. vertex and wall > 200 cm)
- * Events too close to the wall are difficult to accurately reconstruct vertex
- * Reject events which are originated outside the ID
- * Define FV 22.5kton
- 3. Single electron (# of ring is one & e-like)



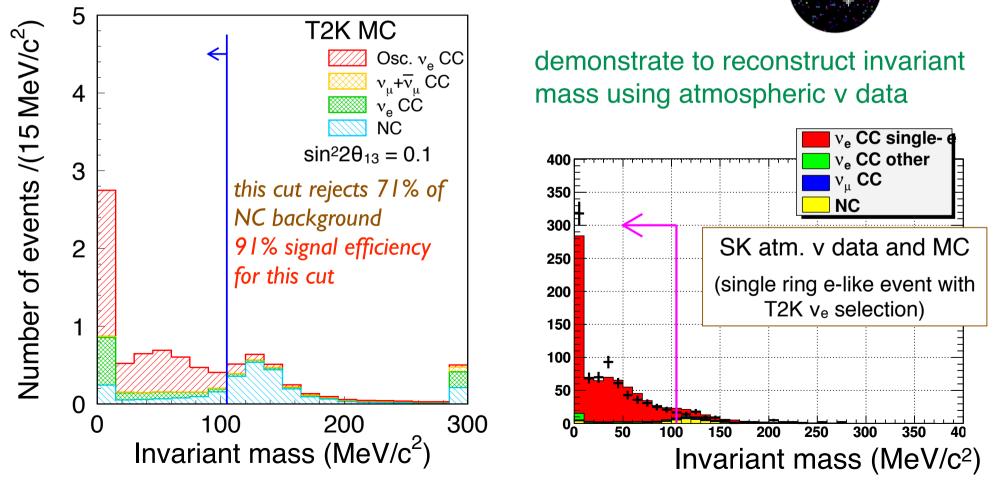




6. Reconstructed invariant mass $(M_{inv}) < 105 \text{ MeV/c}^2$

* Suppress NC π⁰ background

Find 2nd e-like ring by forcing to fit light pattern under the 2 e-like rings assumption, and then ⁰10 -8 reconstruct invariant mass of these 2 e-like rings

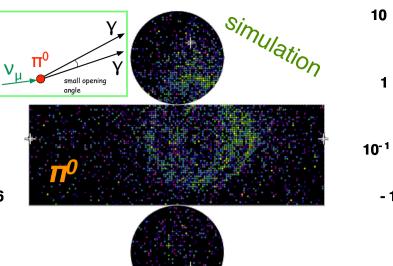


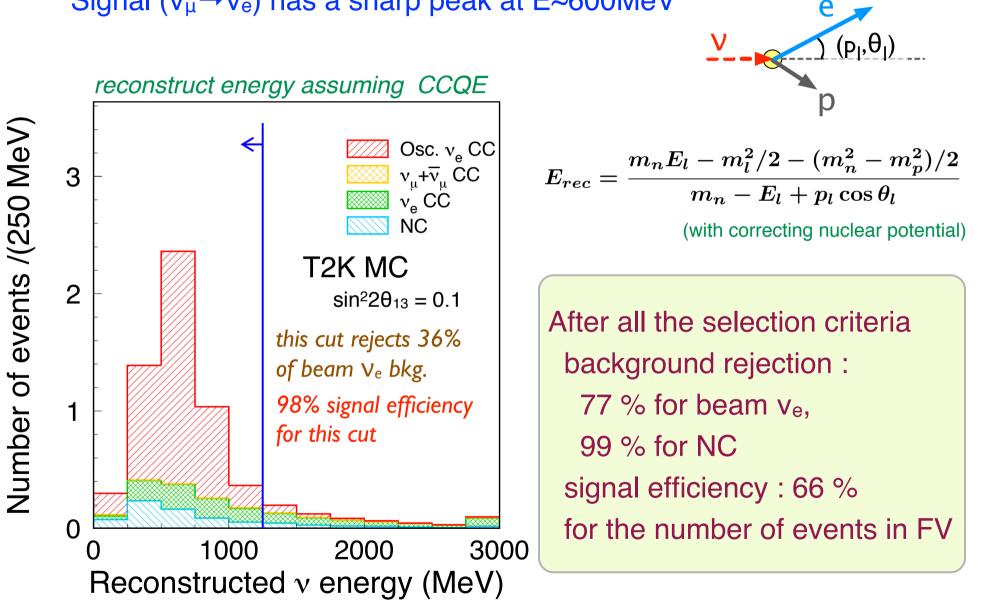
100

80

60

40





- 7. Reconstructed energy $(E_{rec}) < 1250 \text{ MeV}$
 - * Reject intrinsic beam ve backgrounds at high energy
 - * Signal ($v_{\mu} \rightarrow v_{e}$) has a sharp peak at E~600MeV

\checkmark v_e selection criteria

The expected number of events at Far detector with 1.43 x 10²⁰ p.o.t.

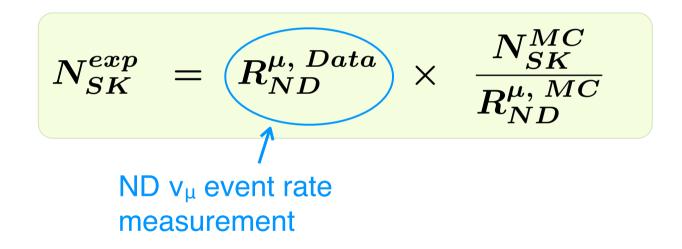
Systematic uncertainty

Observation at Far detector & Results

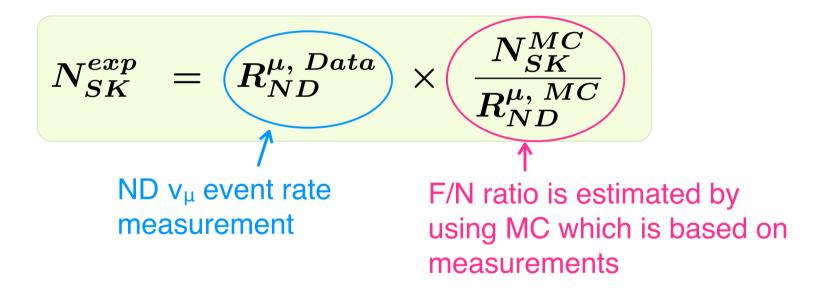
The number of signal and background events are derived by the # of observed v_{μ} event rate at near detector ($R^{\mu,Data}_{ND}$) and the ratio of the expected events at the far detectors and the expected event rate at the near detector (F/N ratio)

$$N_{SK}^{exp} ~=~ R_{ND}^{\mu, ~Data} ~ imes ~~ rac{N_{SK}^{MC}}{R_{ND}^{\mu, ~MC}}$$

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$$N_{SK}^{exp} \;=\; \left(R_{ND}^{\mu,\;Data}
ight) imes \left(rac{N_{SK}^{MC}}{R_{ND}^{\mu,\;MC}}
ight)$$

ND v_{μ} event rate

Measurement of the number of inclusive v_{μ} charged-current events in ND per p.o.t. using data collected in Run 1 (2.88 x 10¹⁹ p.o.t.)

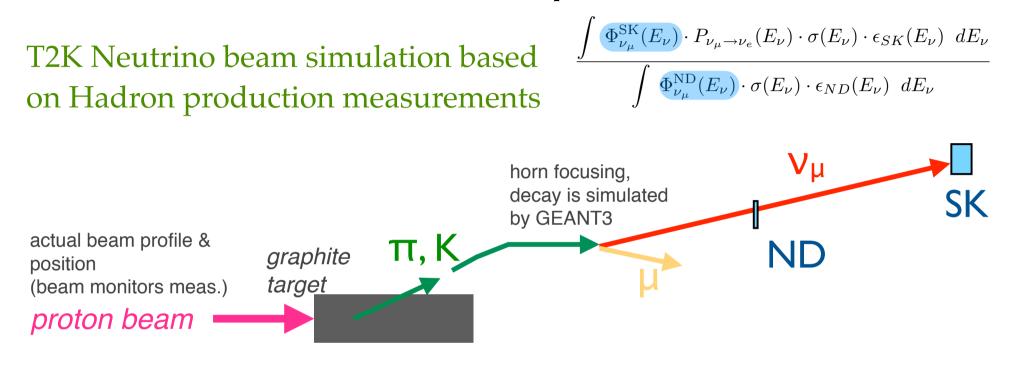
Stability of the beam event rate is confirmed by INGRID measurement *INGRID v int. rate stability Run 1+2/Run 1 < 1%*

F/N ratio for ve signal event

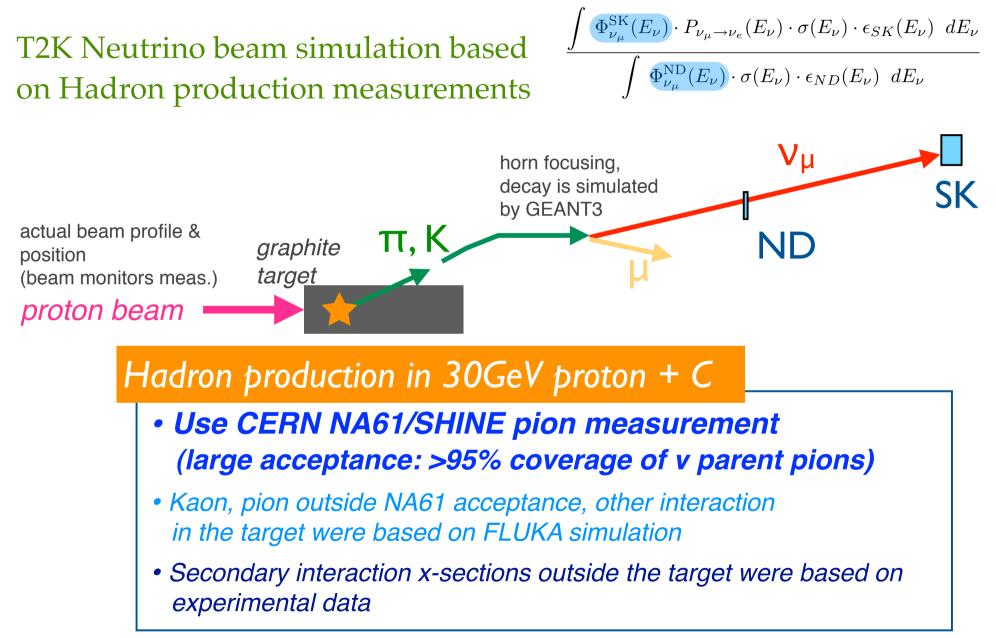
(flux) x (osc. prob.) x (x-section) x (efficiency) x (det. mass)

$$\frac{N_{SK \nu_e \ sig.}^{MC}}{R_{ND}^{\mu, \ MC}} = \frac{\int \Phi_{\nu_{\mu}}^{SK}(E_{\nu}) \cdot P_{\nu_{\mu} \to \nu_e}(E_{\nu}) \cdot \sigma(E_{\nu}) \cdot \epsilon_{SK}(E_{\nu}) \ dE_{\nu}}{\int \Phi_{\nu_{\mu}}^{ND}(E_{\nu}) \cdot \sigma(E_{\nu}) \cdot \epsilon_{ND}(E_{\nu}) \ dE_{\nu}} \cdot \frac{M^{SK}}{M^{ND}} \cdot \text{POT}^{SK}$$

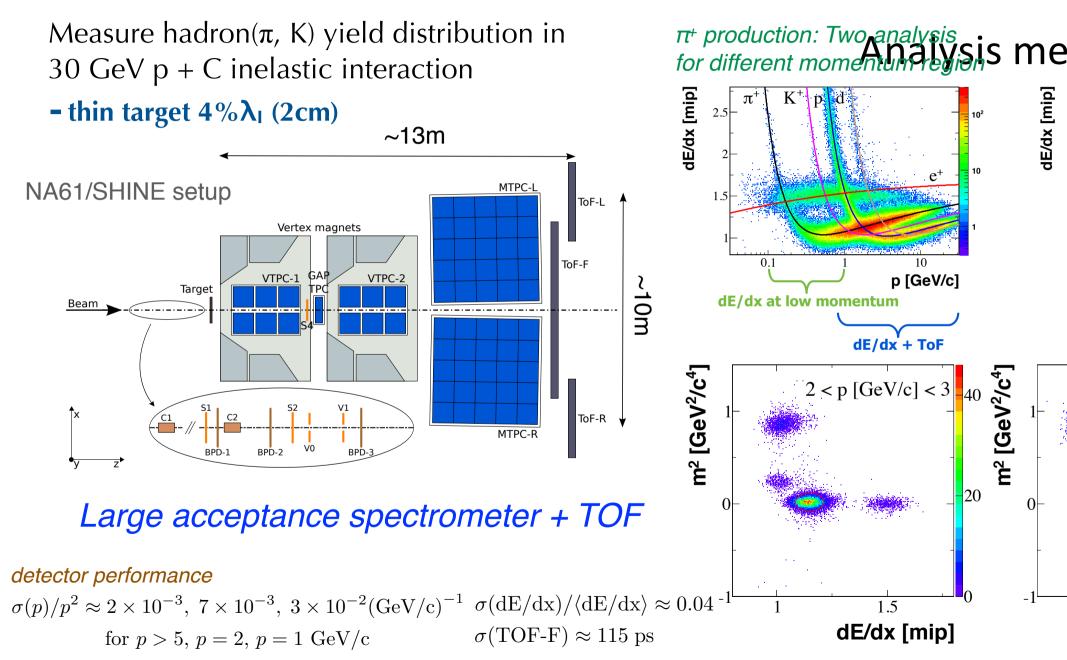
Neutrino flux prediction



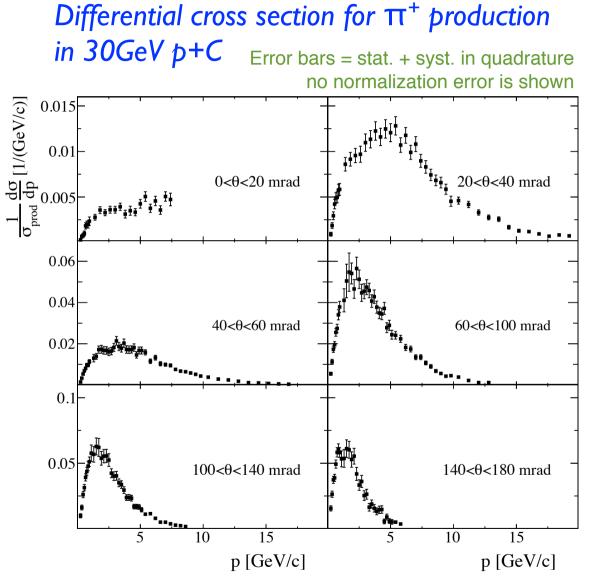
Neutrino flux prediction



CERN NA61/SHINE measurement



Results of pion production from thin target (2007 data)



N.Abgrall et al., arXiv:1102.0983 [hep-ex] submitted to Phys.Rev.C (2011)

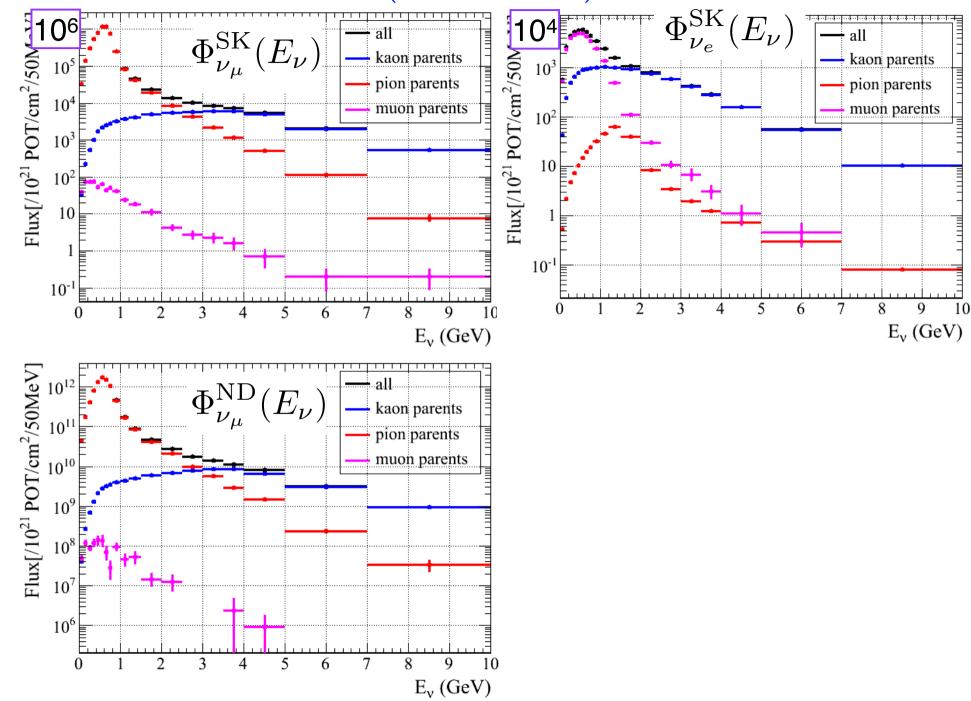
Systematic uncertainty was evaluated in each (p,θ) bin typically 5-10%

The normalization uncertainty is 2.3% on the overall (p, θ)

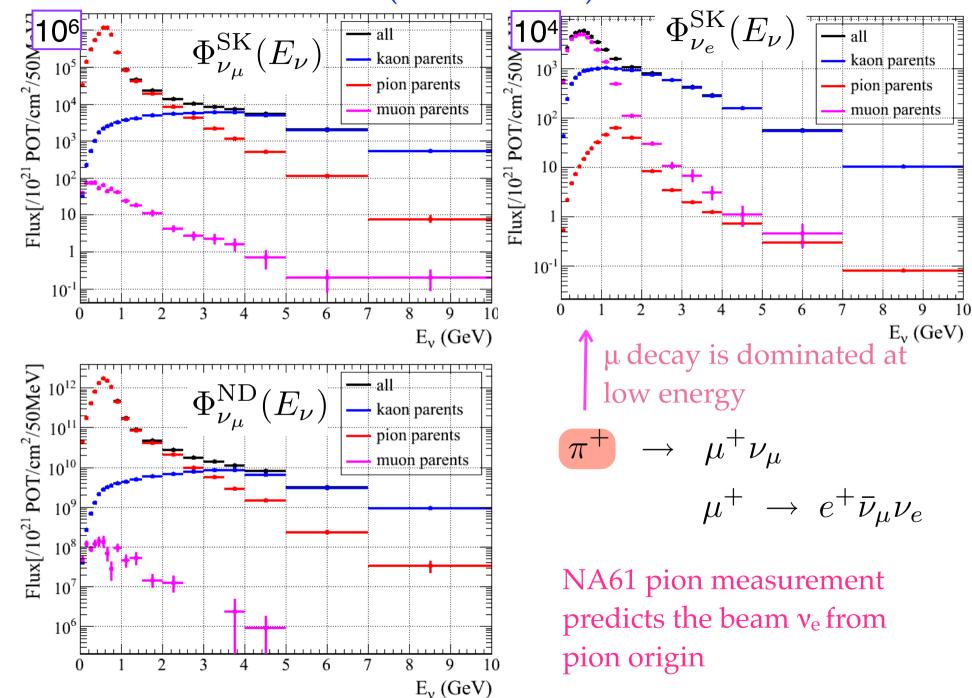
→ Propagate the systematic uncertainty in each (p, θ) bin into the expected number of events in T2K

→ Input to T2K neutrino beam simulation

Predicted neutrino flux (center value)

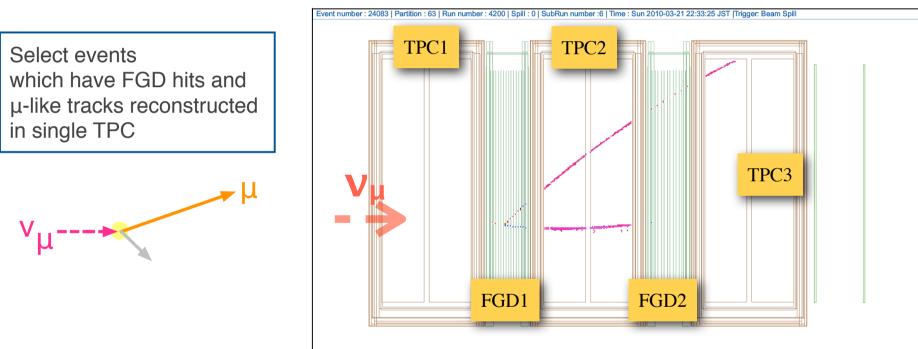


Predicted neutrino flux (center value)



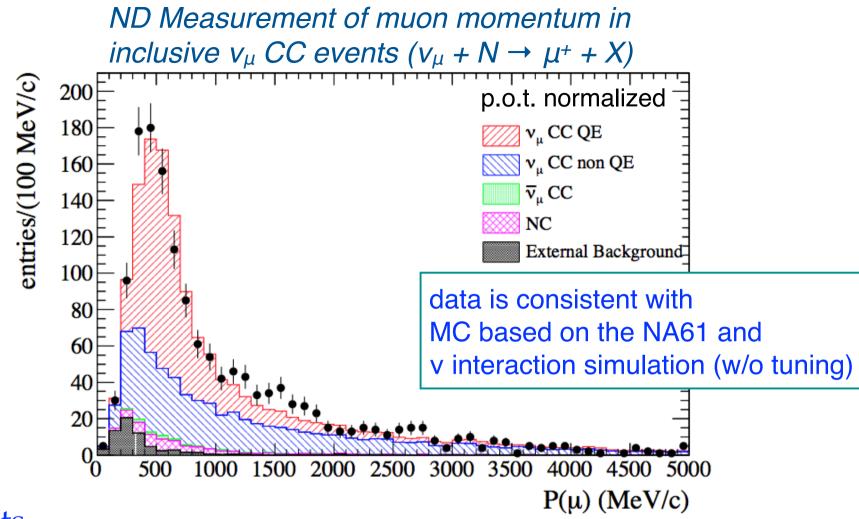
ν_{μ} interaction rates at near detector

• Measure # of inclusive v_{μ} charged current interaction (N^{Data}_{ND})



High purity : 90% v_{μ} Charged Current int. (50% CCQE)

Event display (data)



Results

$$\begin{aligned} R_{ND}^{\mu, \ Data} &= 1529 \text{ events } / \ 2.9 \times 10^{19} \text{ p.o.t.} \\ \\ \frac{R_{ND}^{\mu, \ Data}}{R_{ND}^{\mu, \ MC}} &= 1.036 \pm 0.028(\text{stat.})^{+0.044}_{-0.037}(\text{det. syst.}) \pm 0.038(\text{phys. syst.}) \end{aligned}$$

Intrinsic Beam v_e background at Far detector

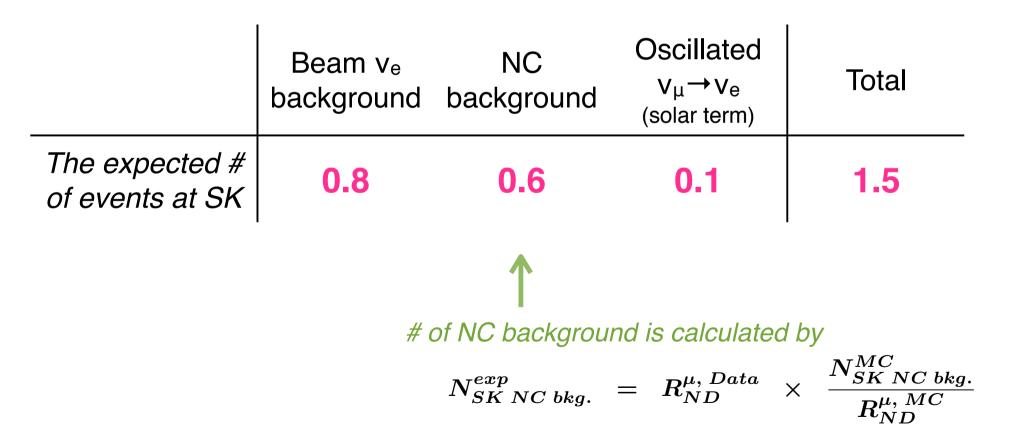
- The number of beam v_e background events at far detector is predicted using the v beam simulation based on NA61 measurements (pion) and FLUKA (kaon)
 - ND measurements (μ momentum and event rate) are consistent with MC based on the ν beam simulation

$$N_{SK\ beam\ \nu_e\ bkg.}^{exp} = R_{ND}^{\mu,\ Data} \times \underbrace{\frac{N_{SK\ beam\ \nu_e\ bkg.}^{MC}}{R_{ND}^{\mu,\ MC}}}_{I_{ND}^{\mu,\ MC}} \times \underbrace{\frac{N_{SK\ beam\ \nu_e\ bkg.}^{MC}}{R_{ND}^{\mu,\ MC}}}_{I_{ND}^{\mu,\ MC}} \times \underbrace{\frac{N_{SK\ beam\ \nu_e\ bkg.}^{MC}}{R_{ND}^{\mu,\ MC}}}_{\int \Phi_{\nu_e}^{SK}(E_{\nu}) \cdot \sigma(E_{\nu}) \cdot \sigma(E_{\nu}) \cdot \epsilon_{SK}(E_{\nu})\ dE_{\nu}}} \cdot \frac{M_{ND}^{SK}}{M^{ND}} \cdot POT^{SK}}$$

The expected number of events for $\sin^2 2\theta_{13}=0$

The expected number of events with 1.43 x 10²⁰ p.o.t.

 $N^{exp}_{SK tot.} = 1.5 \text{ events}$



\checkmark v_e selection criteria

The expected number of events at Far detector

Systematic uncertainty

Observation at Far detector & Results

Systematic uncertainty on N^{exp}_{SK}

| | error source | syst. error | |
|---|--|--|--|
| | (1) ν flux | $\pm 8.5\%$ | <i>for sin²2θ₁₃=0</i> |
| | (2) $ u$ int. cross section | $\pm 14.0\%$ | |
| | (3) Near detector | $^{+5.6}_{-5.2}\%$ | |
| | (4) Far detector | $\pm 14.7\%$ | |
| | (5) Near det. statistics | $\pm 2.7\%$ | |
| | Total | $^{+22.8}_{-22.7}\%$ | |
| $N^{exp}_{SK} = rac{R^{\mu, \ D}_{ND}}{R^{\mu, \ D}_{ND}}$ | $\overset{ata}{	imes} 	imes ~ rac{N^{MC}_{SK}}{R^{\mu,~MC}_{ND}}$ | ➡ N ^{exp} SK | =1.5±0.3 events |
| | $\int \Phi_{\nu_{\mu}(\nu_{e})}^{\rm SK}(E_{\nu})$ | $\cdot P_{osc.}(E_{\nu}) \cdot \sigma($ | $\left(\frac{E_{\nu}}{E_{\nu}}\right) \cdot \epsilon_{SK}(E_{\nu}) \ dE_{\nu}$ |
| | $\int \Phi_{ u_{\mu}}^{ m ND}$ | $(E_{\nu}) \cdot \frac{\sigma(E_{\nu})}{\sigma(E_{\nu})} \cdot \epsilon_{I}$ | $_{ND}(E_{\nu}) \ dE_{\nu}$ |

Systematic uncertainty on N^{exp}_{SK}

| error source | syst. error | |
|--|---|--|
| $O(1) \nu$ flux | $\pm 8.5\%$ | for $sin^{2}2\theta_{13}=0$ |
| $O(2)$ ν int. cross section | $\pm 14.0\%$ | |
| (3) Near detector | $^{+5.6}_{-5.2}\%$ | |
| O(4) Far detector | $\pm 14.7\%$ | |
| (5) Near det. statistics | $\pm 2.7\%$ | |
| Total | $+22.8 \ \% -22.7 \ \%$ | |
| $N_{SK}^{exp} ~=~ oldsymbol{R_{ND}^{\mu, ~Data}} ~	imes~ rac{N_{SK}^{MC}}{R_{ND}^{\mu, ~MC}}$ | ➡ N ^{exp} SK | =1.5±0.3 events |
| $\int \Phi_{\nu_{\mu}(\nu_{e})}^{\rm SK}(E_{\nu})$ | $\cdot P_{osc.}(E_{\nu}) \cdot \sigma($ | $\left \frac{E_{\nu}}{E_{\nu}} \right \cdot \epsilon_{SK}(E_{\nu}) \ dE_{\nu}$ |
| | $\left E_{ u} ight) \cdot \frac{\sigma(E_{ u})}{\sigma(E_{ u})} \cdot \epsilon_{I}$ | |

Neutrino flux uncertainty

Uncertainties in hadron production and interaction are dominant sources $(2) \ \nu \text{ cross section}$ (3) Near detector (4) Far detector (5) Near det. statistics (5) Near det. statistics

error source

(1) ν flux

Error source

- Pion production
 - NA61 systematic uncertainty in each pion's (p, θ) bin
- Kaon production
 - Used model (FLUKA) is compared with the data(Eichten et. al.) in each kaon's (p, θ) bin
- Secondary nucleon production
 - Used model (FLUKA) is compared with the experimental data
- Secondary interaction cross section
 - Used model (FLUKA and GCALOR) is compared with the experimental data of interaction x-section (π, K and nucleon)



graphite target

Summary of v flux uncertainties on N^{exp}_{SK} for $sin^22\theta_{13}=0$

| | N_{SK}^{exp} | = | $R_{ND}^{\mu,\ Data}$ | $	imes ~~ rac{N^{MC}_{SK}}{R^{\mu,~MC}_{ND}}$ |
|------------------------------|----------------|---|---|--|
| Error source | | | $\frac{N_{SK}^{MC}}{R_{ND}^{\mu,\ MC}}$ | _ |
| Pion production | | | 2.5% | |
| Kaon production | | | 7.6% | Hadron |
| Nucleon production | | | 1.4% | production |
| Production x-section | | | 0.7% | & interaction |
| Proton beam position/profile | | | 2.2% | |
| Beam direction measurement | | | 0.7% | |
| Target alignment | | | 0.2% | |
| Horn alignment | | | 0.1% | |
| Horn abs. current | | | 0.3% | |
| Total | | | 8.5% |) |

The uncertainty on N^{exp}_{SK} due to the beam flux uncertainty is **8.5**%

 ΛI

Summary of v flux uncertainties on N^{exp}_{SK} for $sin^22\theta_{13}=0$

| | | $N^{exp}_{SK} =$ | $R_{ND}^{\mu,\;Data}$ | $	imes \; \; rac{N^{MC}_{SK}}{R^{\mu,MC}_{ND}}$ |
|------------------------------|---------------------|------------------|--|--|
| Error source | $R^{\mu,\;MC}_{ND}$ | N_{SK}^{MC} | $\frac{N_{SK}^{MC}}{R_{ND}^{\mu, \ MC}}$ | |
| Pion production | 5.7% | 6.2% | 2.5% | |
| Kaon production | 10.0% | 11.1% | 7.6% | Hadron |
| Nucleon production | 5.9% | 6.6% | 1.4% | production |
| Production x-section | 7.7% | 6.9% | 0.7% | & interaction |
| Proton beam position/profile | 2.2% | 0.0% | 2.2% | |
| Beam direction measurement | 2.7% | 2.0% | 0.7% | |
| Target alignment | 0.3% | 0.0% | 0.2% | |
| Horn alignment | 0.6% | 0.5% | 0.1% | |
| Horn abs. current | 0.5% | 0.7% | 0.3% | |
| Total | 15.4% | 16.1% | 8.5% |) |
| | | | | |

The uncertainty on N^{exp}_{SK} due to the beam flux uncertainty is 8.5% Error cancellation works for some beam uncertainties

NTMC

v int. cross section uncertainty

Evaluate uncertainty on F/N ratio by varying the cross section within its uncertainty

| Main v interaction in each event category- |
|--|
| NC background : NC1 π^0 |
| Beam v_e background : v_e CCQE |
| Signal : v _e CCQE |
| ND CC event : CCQE(50%) |
| CC1π(23%) |
| |

| Cross section uncertainty | | | | |
|---------------------------|---|--|--|--|
| Process | relative to the CCQE total x-section | | | |
| CCQE | energy dependent ($\sim \pm 7\%$ at 500 MeV) | | | |
| CC 1π | $30\% (E_{\nu} < 2 \text{ GeV}) - 20\% (E_{\nu} > 2 \text{ GeV})$ | | | |
| CC coherent π^{0} | 100% (upper limit from [30]) | | | |
| CC other | $30\% (E_{\nu} < 2 \text{ GeV}) - 25\% (E_{\nu} > 2 \text{ GeV})$ | | | |
| NC $1\pi^0$ | $30\% (E_{\nu} < 1 \text{ GeV}) - 20\% (E_{\nu} > 1 \text{ GeV})$ | | | |
| NC coherent π | 30% | | | |
| NC other π | 30% | | | |
| Final State Int. | energy dependent (~ $\pm 10\%$ at 500 MeV) | | | |
| TT (' ' | | | | |

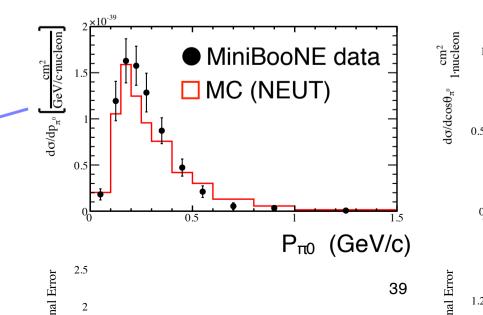
Uncertainty of $\sigma(v_e) / \sigma(v_\mu) = \pm 6\%$

error source

- (1) ν flux
- (2) ν cross section
- (3) Near detector
- (4) Far detector
- (5) Near det. statistics

$$\frac{\int \Phi_{\nu_{\mu}(\nu_{e})}^{\mathrm{SK}}(E_{\nu}) \cdot P_{osc.}(E_{\nu}) \cdot \sigma(E_{\nu}) \cdot \epsilon_{SK}(E_{\nu}) \ dE_{\nu}}{\int \Phi_{\nu_{\mu}}^{\mathrm{ND}}(E_{\nu}) \cdot \sigma(E_{\nu}) \cdot \epsilon_{ND}(E_{\nu}) \ dE_{\nu}}$$

Cross section uncertainties are estimated by Data/MC comparison, model comparison and parameter variation



error source

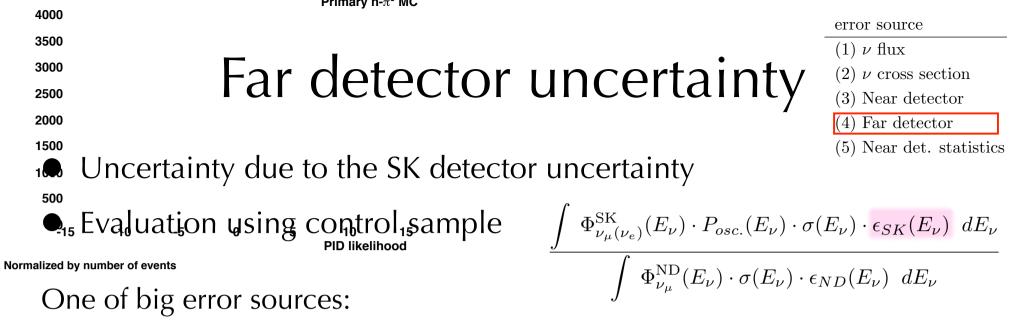
v int. cross section uncertainty on N^{exp}_{SK} for sin²2 θ_{13} =0

(1) ν flux

- (2) ν cross section
- (3) Near detector
- (4) Far detector
- (5) Near det. statistics

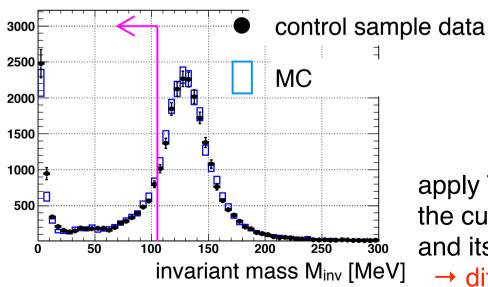
| Error source | syst. error on N_{SK}^{exp} | |
|---------------------|-------------------------------|---------------------------|
| CC QE shape | 3.1% | - |
| $\mathrm{CC} 1\pi$ | 2.2% | |
| CC Coherent π | 3.1% | |
| CC Other | 4.4% | |
| NC $1\pi^0$ | 5.3% | |
| NC Coherent π | 2.3% | |
| NC Other | 2.3% | |
| $\sigma(u_e)$ | 3.4% | Uncertainty in pion's |
| \mathbf{FSI} | 10.1% | ← final state interaction |
| Total | (14.0%) | is dominant |
| | | |

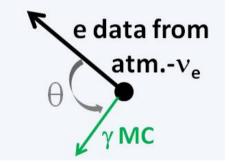
The uncertainty on N^{exp}_{SK} due to the v x-section uncertainty is 14% $(\sin^2 2\theta_{13}=0)$



detection efficiency of NC 1π⁰ background

control sample with one data electron + one simulated γ





apply T2K v_{e} selection and compare the cut efficiency between control sample data and its MC

 \rightarrow difference is assigned as sys. error

Summary of Far detector systematic uncertainty

| Error source | $\left \frac{\delta N^{MC}_{SK \ \nu_e \ sig.}}{N^{MC}_{SK \ \nu_e \ sig.}} \right $ | $\frac{\delta N^{MC}_{SK\ bkg.\ tot.}}{N^{MC}_{SK\ bkg.\ tot.}}$ | |
|--------------------------|---|--|------------------------------|
| π^0 rejection | - | 3.6% | |
| Ring counting | 3.9% | 8.3% | Evaluated by |
| Electron PID | 3.8% | 8.0% | Evaluated by atmospheric |
| Invariant mass cut | 5.1% | 8.7% | v _e enriched data |
| Fiducial volume cut etc. | 1.4% | 1.4% | |
| Energy scale | 0.4% | 1.1% | |
| Decay electron finding | 0.1% | 0.3% | |
| Muon PID | - | 1.0% | |
| Total | 7.6% | 15% | |

→ The total uncertainty on $N^{MC}_{SK tot.}$ is **14.7** % (sin²2 θ_{13} =0) (uncertainty on the background + solar term oscillated v_e)

Total Systematic uncertainties

Summary of systematic uncertainties on N^{exp}_{SK total.} for sin²20₁₃=0

| Error source | $\sin^2 2\theta_{13} = 0$ |
|--|---------------------------|
| O(1) Beam flux | $\pm 8.5\%$ |
| $\mathbf{O}(2)$ ν int. cross section | $\pm 14.0\%$ |
| (3) Near detector | $^{+5.6}_{-5.2}\%$ |
| O(4) Far detector | $\pm 14.7\%$ |
| (5) Near det. statistics | $\pm 2.7\%$ |
| Total | +22.80% -22.7% |

*cf. sin*²2θ₁₃=0: #sig = 0.1 #bkg = 1.4

 $N^{exp}_{SK tot.} = 1.5 \pm 0.3$ events for sin²2 θ_{13} =0 (w/ 1.43 x 10²⁰ p.o.t.)

Total Systematic uncertainties

Summary of systematic uncertainties on N^{exp}_{SK total.} for sin²20₁₃=0 and 0.1

| Error source | $\sin^2 2\theta_{13} = 0$ | $\sin^2 2\theta_{13} = 0.1$ | cf. |
|--|------------------------------------|------------------------------------|--|
| O(1) Beam flux | $\pm 8.5\%$ | $\pm 8.5\%$ | sin²20 ₁₃ =0: #sig = 0.1 #bkg = 1.4 |
| $O(2) \nu$ int. cross section (3) Near detector | $\pm 14.0\%$ $^{+5.6}_{-5.2}\%$ | $\pm 10.5\%$ $^{+5.6}_{-5.2}\%$ | sin ² 2θ ₁₃ =0.1: #sig = 4.1 #bkg = 1.3 |
| O(4) Far detector (5) Near det. statistics | $\pm 14.7\%$ $\pm 2.7\%$ | $\pm 9.4\%$ $\pm 2.7\%$ | |
| Total | +22.80% -22.7% | (-17.5%) | mall Far det. |
| | | | ainty for signal) |

 $N^{exp}_{SK tot.} = 1.5 \pm 0.3$ events for sin²2 θ_{13} =0 (w/ 1.43 x 10²⁰ p.o.t.)

\checkmark v_e selection criteria

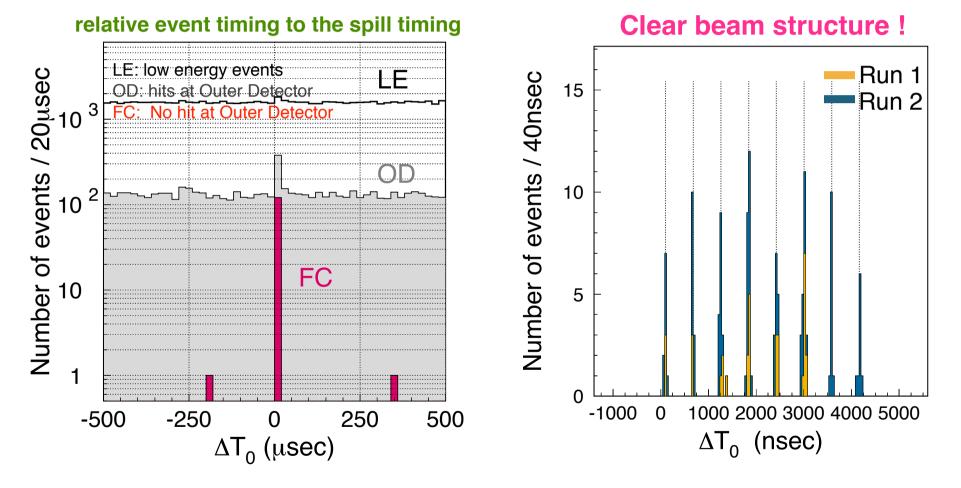
The expected number of events at Far detector

Systematic uncertainty

Observation at Far detector & Results

SK events in beam timing

• Events in the T2K beam timing synchronized by GPS



 $\Delta T_0 = T_{GPS} @SK - T_{GPS} @J-PARC - TOF(~985 \mu sec)$

Number of T2K events at far detector

Number of events in on-timing windows (-2 \sim +10 μ sec)

| Class / Beam run | RUN-1 | RUN-2 | Total | non-beam | |
|---------------------------|-------|-------|-------|------------|--|
| POT (x 10 ¹⁹) | 3.23 | 11.08 | 14.31 | background | |
| Fully-Contained (FC) | 33 | 88 | 121 | 0.023 | |

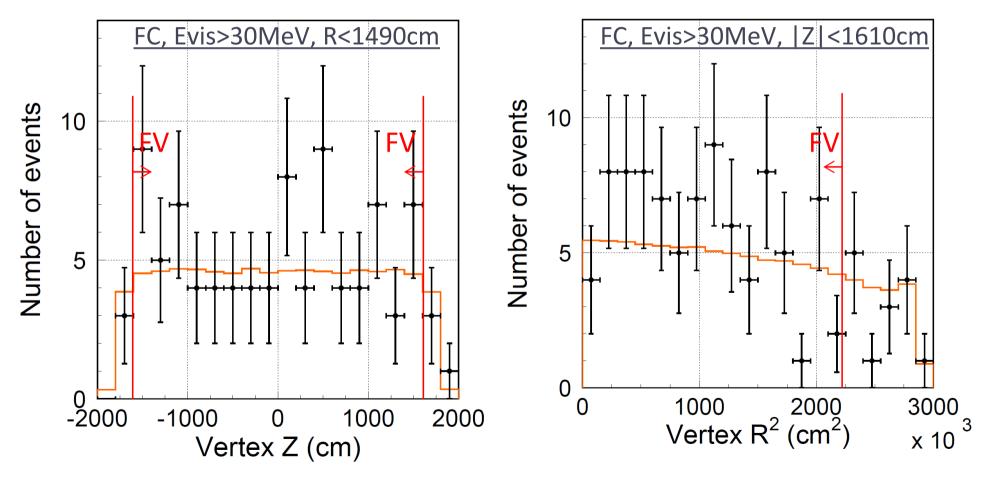
The accidental contamination from atmospheric v background is estimated using the sideband events to be 0.023

Apply ν_e event selection

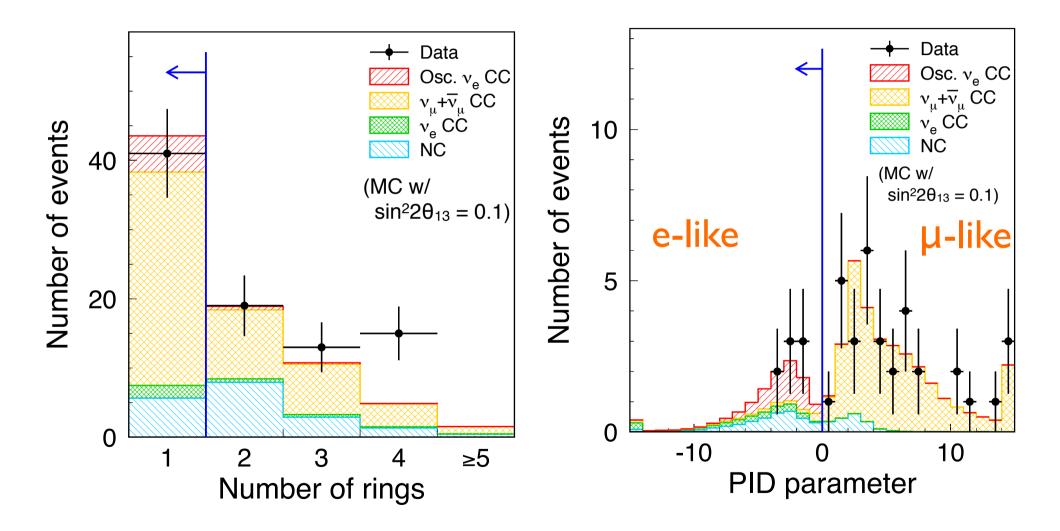
defined before the data collection 6 selection cuts in addition FC cut

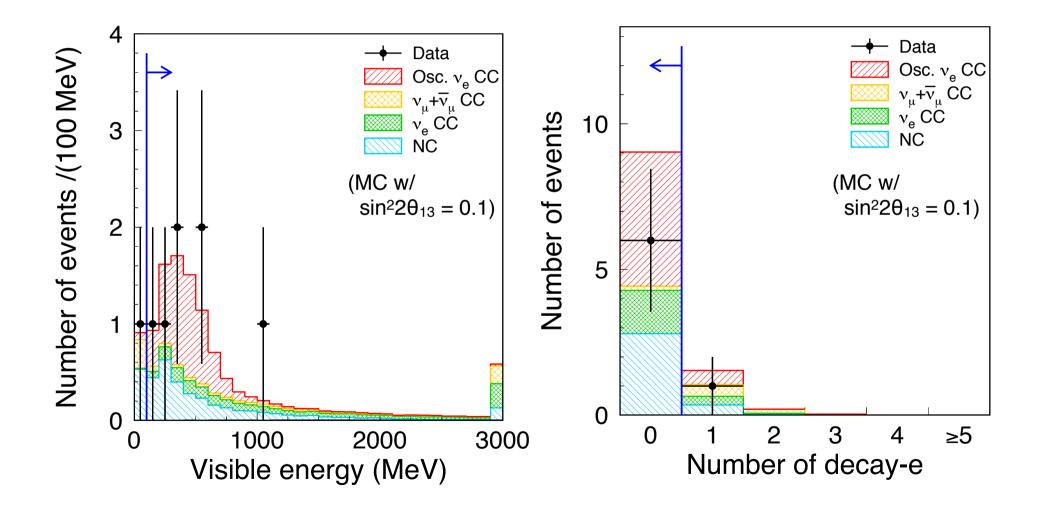
Fiducial volume cut

(distance between recon. vertex and wall > 200cm)

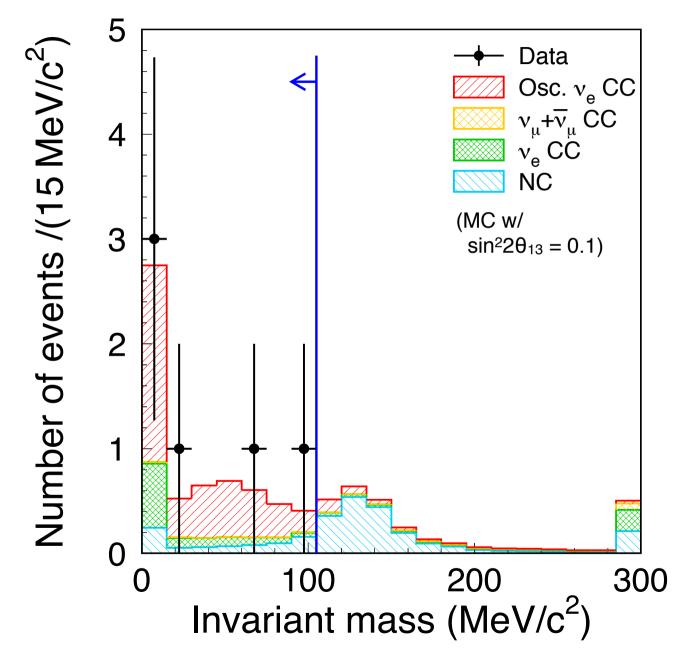


Single electron cut (# of ring is one & e-like)

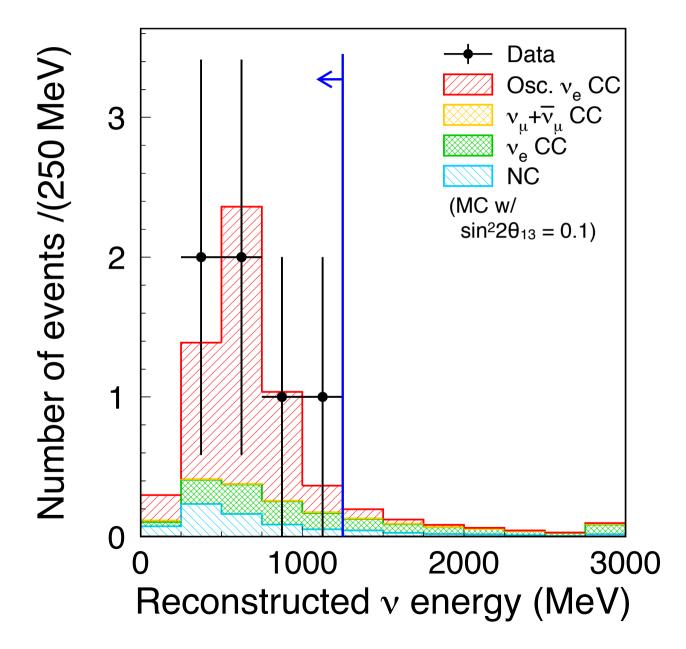




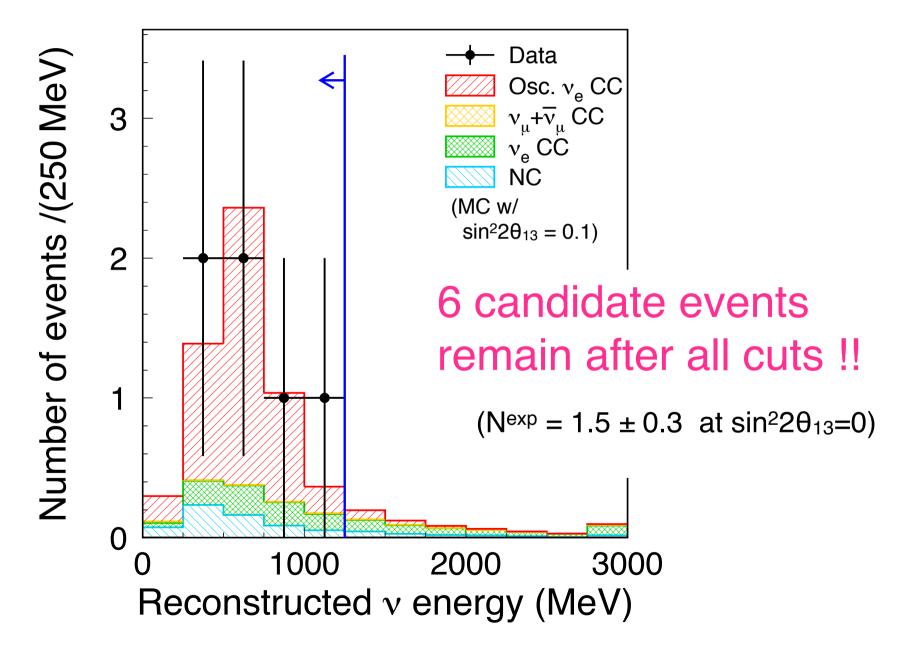
Invariant mass cut ($M_{inv} < 105 \text{ MeV/c}^2$)



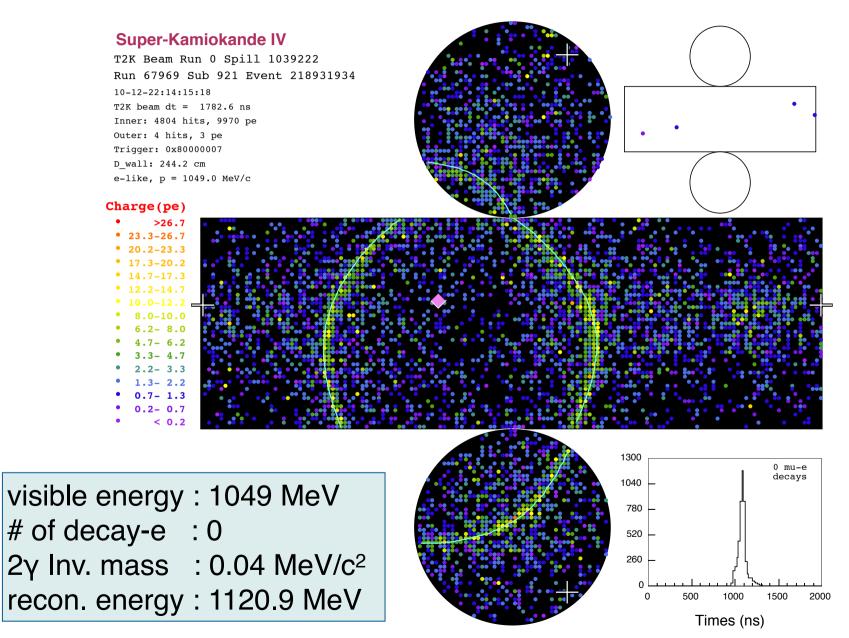
Reconstructed v energy cut ($E_{rec} < 1250 \text{ MeV}$) : Final cut



Reconstructed v energy cut ($E_{rec} < 1250 \text{ MeV}$) : Final cut

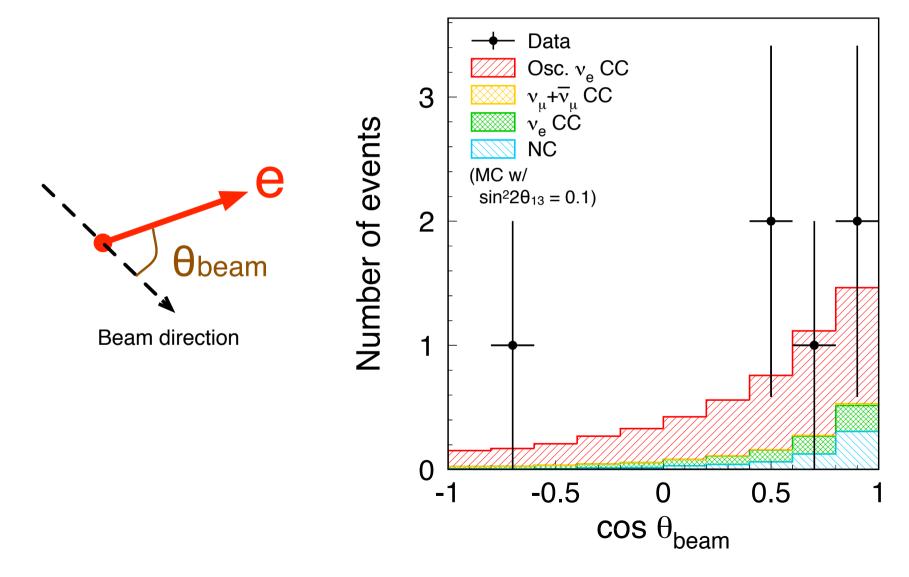


ν_e candidate event

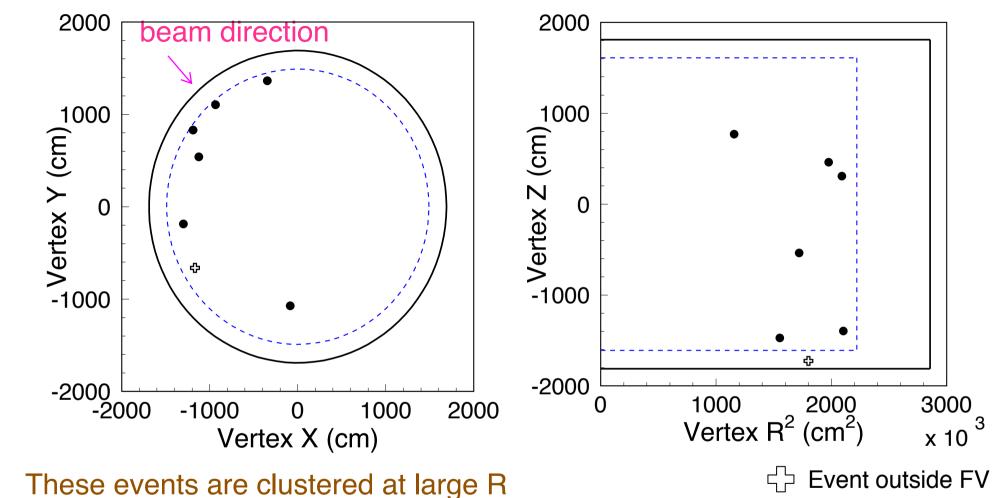


Further check

Check several distribution of v_e candidate events



Vertex distribution of v_e candidate events



 \rightarrow Perform several checks. for example

- * Check distribution of events outside FV \rightarrow no indication of BG contamination
- * Check distribution of OD events \rightarrow no indication of BG contamination
- * K.S. test on the R² distribution yields a p-value of 0.03

Results for v_e appearance search with 1.43 x 10²⁰ p.o.t.

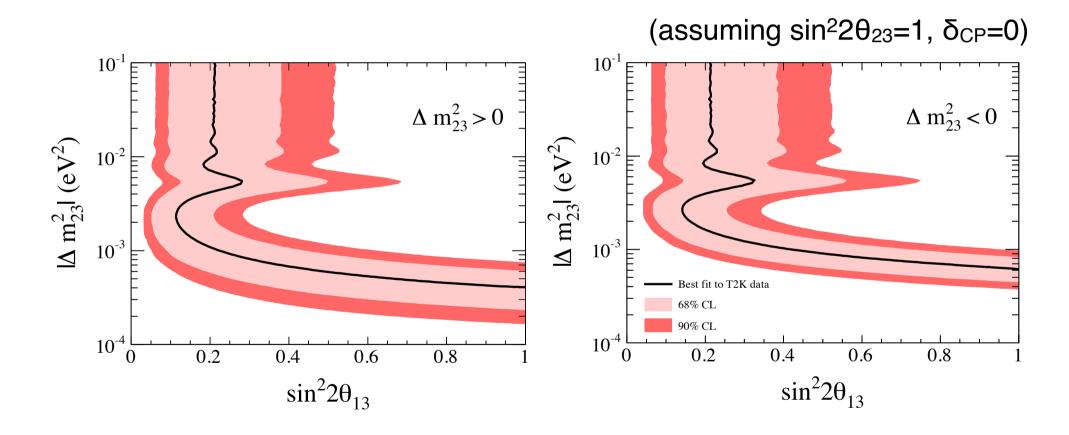
The observed number of events is **6**

The expected number of events is 1.5 ± 0.3

for $\sin^2 2\theta_{13}=0$

Under the θ_{13} =0 hypothesis, the probability to observe six or more candidate events is 0.007 (equivalent to 2.5 σ significance)

Allowed region of $\sin^2 2\theta_{13}$ as a function of Δm^2_{23}



Feldman-Cousins method was used

Allowed region of $sin^2 2\theta_{13}$ as a function of δ_{CP}

(assuming $\Delta m^2_{23}=2.4 \times 10^{-3} \text{ eV}^2$, sin²2 $\theta_{23}=1$) $\Delta m_{23}^2 > 0$ $\Delta m_{23}^2 < 0$ $\pi/2$ $\pi/2$ $\delta_{\rm CP}$ $\delta_{\rm CP}$ 0 0 T2K Best fit to T2K data $-\pi/2$ $-\pi/2$ 1.43×10^{20} p.o.t. 68% CL 90% CL -π -π 0.1 0.2 0.3 0.5 0.1 0.2 0.3 0.5 0.4 0.6 0.4 0.6 0 0 $\sin^2 2\theta_{13}$ $\sin^2 2\theta_{13}$

90% C.L. interval & Best fit point (assuming Δm²₂₃=2.4 x 10⁻³ eV², sin²2θ₂₃=1, δ_{CP}=0)

 $\begin{array}{ll} 0.03 < \sin^2 2\theta_{13} < 0.28 & 0.04 < \sin^2 2\theta_{13} < 0.34 \\ & \sin^2 2\theta_{13} = 0.11 & \sin^2 2\theta_{13} = 0.14 \end{array}$

T2K Next steps

Aim for firmly establishing v_e appearance and better determining the angle θ_{13}

- Resume experiment
 - Recovery works in progress
 - We will resume J-PARC activity including accelerator complex and neutrino facility by December, 2011
 - Neutrino facility will be ready by November
- Analysis improvement
 - New analysis methods using $\nu_{\rm e}$ signal shape (e.g. recon. energy) are under development

Conclusion

- We reported new results on $v_{\mu} \rightarrow v_{e}$ oscillation analysis based on 1.43 x 10²⁰ p.o.t. (2% exposure of T2K's goal)
 - The expected number of events is 1.5 ± 0.3 (sin²2 $\theta_{13} = 0$)
 - 6 candidate events are observed
 - Under θ₁₃=0 hypothesis, the probability to observe 6 or more candidate events is 0.007 (equivalent to 2.5 σ significance)
 - $0.03 (0.04) < \sin^2 2\theta_{13} < 0.28 (0.34) \text{ at } 90\% \text{ C.L. for normal (inverted) hierarchy} \\ (\text{assuming } \Delta \text{m}^2_{23} = 2.4 \text{ x } 10^{-3} \text{ eV}^2, \sin^2 2\theta_{23} = 1, \delta_{\text{CP}} = 0)$

Indication of v_e appearance

submitted to PRL

- Resume experiment as soon as possible and improve analysis method to conclude v_e appearance phenomenon
- v_{μ} disappearance result with 1.43 x 10²⁰ p.o.t. data will be reported this summer